

Appl. No. : 10/766,371
Filed : January 27, 2004

REMARKS

The Applicant thanks the Examiner for his careful and thoughtful examination of the present application. By way of summary, Claims 13-22 and 33-36 were pending in this application. In the present amendment, the Applicant has amended Claims 13, 15, 21, 22 and 33-36 and has added Claims 37-52. Accordingly, Claims 13-22 and 33-52 remain pending for consideration.

Amendments to the Claims

The Applicant has amended Claim 13 to further clarify the claimed subject matter. In particular, the Applicant has amended independent Claim 13 to recite a "device for testing a plurality of semiconductor devices, the plurality of semiconductor devices forming a wafer having a plurality of electrical contacts on a first side, and the plurality of electrical contacts comprising substantially every electrical contact on the first side of the wafer, the testing device comprising . . . a plurality of contact members positioned on the at least one flexible membrane and configured to provide an electrical connections to a each of the plurality of electrical contacts on the plurality of semiconductor devices to be tested."

The Applicant has also amended Claims 15, 21, 22 and 33-36 to improve the readability and grammar of these claims. New Claims 37-52 are directed towards systems and devices for testing a plurality of semiconductor devices, and are fully supported by the Application as originally filed.

The Applicant respectfully submits that these amendments add no new matter, and also submits that the new and amended claims are novel and non-obvious over the prior art.

Rejection Under 35 U.S.C. 102(b)

The Examiner rejected Claims 13-17, 19-21, 33 and 34 as being anticipated by U.S. Patent No. 5,623,214 (Pasiecznik, Jr.). The Examiner asserted that Pasiecznik teaches a housing, grid, flexible membrane, contact members and a fluid channel.

In light of the above amendments, the Applicant respectfully traverses this rejection. Applicant has amended independent Claim 13 to recite a "device for testing a plurality of semiconductor devices, the plurality of semiconductor devices forming a wafer having a plurality of electrical contacts on a first side, and the plurality of electrical contacts comprising

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substantially every electrical contact on the first side of the wafer, the testing device comprising . . . a plurality of contact members positioned on the at least one flexible membrane and configured to provide ~~an~~ electrical connections to a each of the plurality of electrical contacts."

The contact pads 30 disclosed by Pasiecznik, in contrast, contact only a subset of the electrical contacts on the die contact pads 37. Indeed, the goal disclosed by Pasiecznik is to provide a device for contacting approximately half of the electrical contacts on the die contact pads 37 at a time, using a two stage process to test the whole wafer. *See* Col. 11, ll. 57-62.

The Applicant's claimed device is not so limited. Instead, the Applicant has disclosed a single device for providing "electrical connections to each of the plurality of electrical contacts" on a first side of the wafer formed by the plurality of semiconductor devices. The Applicant respectfully submits that Claim 13 recites a unique combination of features that are not taught or suggested by the prior art, and requests that the rejections be withdrawn.

Claims 14-22 and 33-38 are dependent upon Claim 13 and are therefore patentable for at least the same reasons given above.

The Applicant has also submitted new independent Claim 39. Claim 39 is a device for testing a plurality of semiconductor devices "wherein each chamber is configured such that the portion of the at least one flexible membrane over each chamber is sized to contact at most one of the plurality of semiconductor devices." Among other reasons, this claim should be allowable over Pasiecznik because Pasiecznik teaches chambers that are configured to contact many dies at once. *See* Col. 12, ll. 8-17.

The Applicant therefore submits that Claims 13-22 and 33-52 recite a unique combination of features not taught or suggested by the prior art. Accordingly, the Applicant respectfully requests that these claims be allowed.

Conclusion

The Applicant has endeavored to address all of the Examiner's concerns as expressed in the outstanding Office Action. In view of the above remarks, the Applicant submits that the application is in condition for allowance and respectfully requests the same. If the Examiner finds any remaining impediment to the prompt allowance of these claims that could be clarified with a telephone conference, the Examiner is invited to initiate the same with the undersigned.


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Please charge any additional fees, including any fees for additional extension of time, or credit overpayment to Deposit Account No. 11-1410.

Respectfully submitted,

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Dated: 4-12-05

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